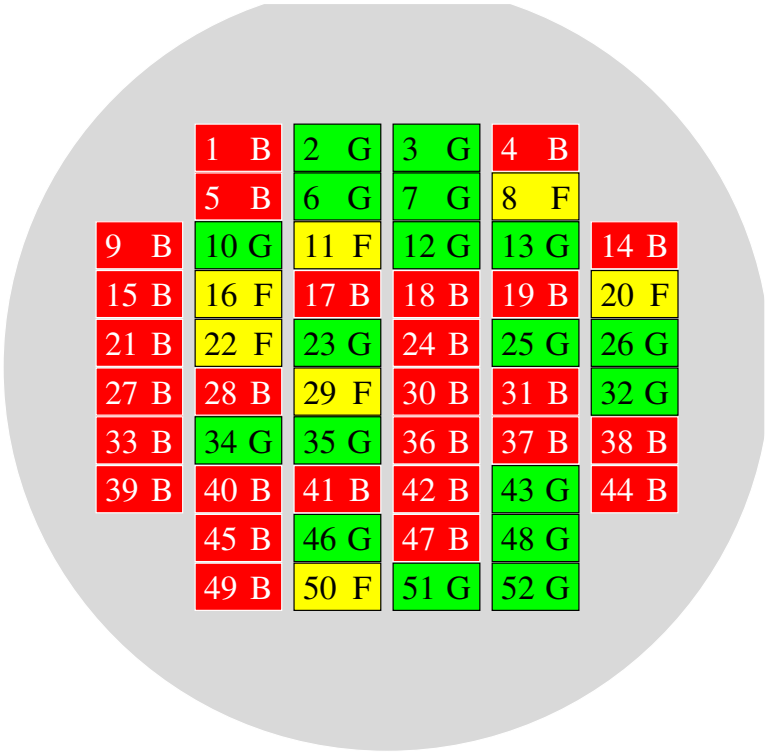
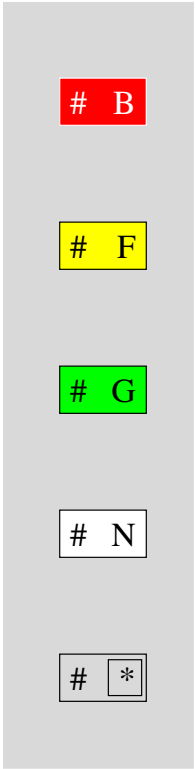
Die quality map for wafer 79 s/n: 21316-04-11

Date: 01/19/99





Bad die

Fair die

Good die

No info

Manually tagged